

**Notice of References Cited**Application/Control No.  
**09/769,170**Applicant(s)/Patent Under Reexam  
**Chu et al**Examiner  
**Edward Wojciechowicz**Art Unit  
**2815**

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**U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification <sup>2</sup>	
		Country Code-Number-Kind Code	MM-YYYY <sup>1</sup>			
x	A	5,856,229	1/1999	Sakaguchi et al	257	347
x	B	5,528,397	6/1996	Zavracky et al	257	347
	C					
	D					
	E					
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	H					
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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